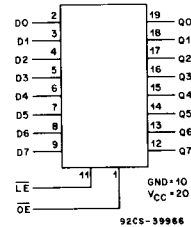


CD54AC573/3A
CD54ACT573/3A

Octal Transparent Latch, 3-State Non-Inverting

The RCA CD54AC573/3A and CD54ACT573/3A are octal transparent 3-state latches that utilize the new RCA ADVANCED CMOS LOGIC technology. The outputs are transparent to the inputs when the Latch Enable (\overline{LE}) is HIGH. When the Latch Enable (\overline{LE}) goes LOW, the data is latched. The Output Enable (\overline{OE}) controls the 3-state outputs. When the Output Enable (\overline{OE}) is HIGH, the outputs are in the high-impedance state. The latch operation is independent of the state of the Output Enable.

The CD54AC573/3A and CD54ACT573/3A are supplied in 20-lead dual-in-line ceramic packages (F suffix).



Package Specifications

See Section 11, Fig. 13

FUNCTIONAL DIAGRAM & TERMINAL ASSIGNMENT

Static Electrical Characteristics (Limits with black dots (•) are tested 100%.)

CHARACTERISTICS	TEST CONDITIONS	V_{CC} (V)	AMBIENT TEMPERATURE (T_A) - °C				UNITS	
			+25		-55 to +125			
			MIN.	MAX.	MIN.	MAX.		
3-State Leakage Current	I_{OZ} V_{IH} or V_{IL} $V_O = V_{CC}$ or GND	5.5	—	$\pm 0.5\bullet$	—	$\pm 10\bullet$	μA	
Quiescent Supply Current (MSI)	I_{CC} V_{CC} or GND	0	5.5	—	$8\bullet$	—	$160\bullet$	μA

The complete static electrical test specification consists of the above by-type static tests combined with the standard static tests in the beginning of this section.

ACT INPUT LOADING TABLE

INPUT	UNIT LOAD*
\overline{OE}	0.87
D_n	0.5
\overline{LE}	0.8

*Unit load is ΔI_{CC} limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25°C.

Burn-In Test-Circuit Connections (Use Static II for /3A burn-in and Dynamic for Life Test.)

Static	STATIC BURN-IN I			STATIC BURN-IN II		
	OPEN	GROUND	V_{CC} (6V)	OPEN	GROUND	V_{CC} (6V)
CD54AC/ACT573	12-19	1-11	20	12-19	10	1-9,11,20
Dynamic	OPEN	GROUND	$1/2 V_{CC}$ (3V)	V_{CC} (6V)	OSCILLATOR	
CD54AC/ACT573	—	1,10	12-19	20	50 kHz	25 kHz
					11	2-9

NOTE: Each pin except V_{CC} and Gnd will have a resistor of 2k-47k ohms.

CD54AC573/3A CD54ACT573/3A

SWITCHING CHARACTERISTICS: AC Series; $t_r, t_f = 3 \text{ ns}$, $C_L = 50 \text{ pF}$ (Limits with black dots (•) are tested 100%.)

CHARACTERISTICS	SYMBOL	V _{CC} (V)	-55 to +125°C		UNITS
			MIN.	MAX.	
Propagation Delays: Data to Qn	t_{PLH}	1.5	—	106	ns
	t_{PHL}	3.3* 5†	3.6 2.6	11.9 8.5•	
\overline{LE} on Qn	t_{PLH}	1.5	—	150	ns
	t_{PHL}	3.3 5	5 3.6	16.8 12•	
Output Enable	t_{PZL}	1.5	—	131	ns
	t_{PZH}	3.3 5	4.4 3.2	14.7 10.5•	
Disable Time	t_{PLZ}	1.5	—	181	ns
	t_{PHZ}	3.3 5	5.4 4.4	18.1 14.5•	
Power Dissipation Capacitance	$C_{PD}\S$	—	63 Typ.		pF
Min. (Valley) V _{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V _{OHV}	5	4 Typ. @ 25°C		V
Max. (Peak) V _{OL} During Switching of Other Outputs (Output Under Test Not Switching)	V _{OLP}	5	1 Typ. @ 25°C		V
Input Capacitance	C _I	—	—	10	pF
3-State Output Capacitance	C _O	—	—	15	pF

SWITCHING CHARACTERISTICS: ACT Series; $t_r, t_f = 3 \text{ ns}$, $C_L = 50 \text{ pF}$ (Limits with black dots (•) are tested 100%.)

CHARACTERISTICS	SYMBOL	V _{CC} (V)	-55 to +125°C		UNITS
			MIN.	MAX.	
Propagation Delays Data to Qn	t_{PLH} t_{PHL}	5†	3.2	10.4•	ns
	t_{PLH} t_{PHL}	5	3.8	12.5•	
Output Enable	t_{PZL} t_{PZH}	5	4.1	13.5•	ns
Disable Time	t_{PLZ} t_{PHZ}	5	3.8	12.5•	ns
Power Dissipation Capacitance	$C_{PD}\S$	—	63 Typ.		pF
Min. (Valley) V _{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V _{OHV}	5	4 Typ. @ 25°C		V
Max. (Peak) V _{OL} During Switching of Other Outputs (Output Under Test Not Switching)	V _{OLP}	5	1 Typ. @ 25°C		V
Input Capacitance	C _I	—	—	10	pF
3-State Output Capacitance	C _O	—	—	15	pF

*3.3 V: min. is @ 3.6 V
max. is @ 3 V

†5 V: min. is @ 5.5 V
max. is @ 4.5 V

§C_{PD} is used to determine the dynamic power consumption per latch.

For AC, $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$

For ACT, $P_D = V_{CC}^2 f_i (C_{PD} + C_L) + V_{CC} \Delta I_{CC}$ where f_i = input frequency

C_L = output load capacitance

V_{CC} = supply voltage